

**Notice of References Cited**

Application/Control No.

10/560,405

Applicant(s)/Patent Under  
Reexamination  
CHARTIER ET AL.

Examiner

John L. Goff

Art Unit

1791

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,251,219	06-2001	Chen et al.	156/556
	B	US-			
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	E	US-			
	F	US-			
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	I	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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